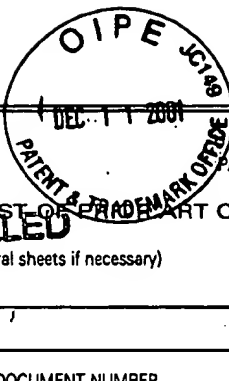


FORM PTO-1449
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APPLICANT(S): Kevin BYNUM, et al.

FILING DATE: July 30, 2001

GROUP: To Be Assigned

LIST OF PRIOR ART CITED BY APPLICANT

DATE CANCELLED
DEC 12 2001 (Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CH	AA	5	2	5	7	1	8	3	Oct. 26, 1993	Tam	364	413.19	
CH	AB	6	0	8	8	1	0	0	Jul. 11, 2000	Brenan, et al.	356	346	
CH	AC	6	0	8	1	3	2	2	Jun. 27, 2000	Barbour	356	73.1	
CH	AD	5	1	3	7	3	5	5	Aug. 11, 1992	Barbour, et al.	356	342	
CH	AE	5	0	7	3	9	1	0	Dec. 17, 1991	Eberhard, et al.	378	4	
CH	AF	5	0	6	8	8	8	2	Nov. 26, 1991	Eberhard	378	4	
CH	AG	5	6	6	4	5	7	4	Sep. 9, 1997	Chance	128	664	
CH	AH	5	4	9	1	5	5	2	Feb. 13, 1996	Knüttel	356	360	
CH	AI	5	4	5	9	5	7	0	Oct. 17, 1995	Swanson, et al.	356	345	
	AJ												
	AK												

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
	AL													
	AM													
	AN													
	AO													
	AP													

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	Thermoelectrically cooled Si Photodiodes, http://www.hamamatsu.com/hp2/products/cool/PDETESIE.htm
CH	AS	Image Processing Toolbox, ver. 2, Mathworks, Inc., Natick, MA, 1998, 6-19 to 6-32 and 11-154
	AT	Image Projections and the Radon Transform, http://www.ece.rice.edu/~elec431/projects96/DSP/panalysis.html

EXAMINER

CONSTANTINE HANNAHER

DATE CONSIDERED

DEC 3 2004

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.